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| Notice of References Cited | Application/Control No. 10/512,003 | Applicant(s)/Patent Under Reexamination BAMBACH, RAMON JOHN | |
| | Examiner Benjamin P. Lee | Art Unit 3641 | Page 1 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-694,896 A | 03-1902 | R. W. Scott | 102/438 |
| * | B | US-2,313,030 A | 03-1943 | GUSTAV TAUSCHEK | 89/135 |
| * | C | US-3,412,681 A | 11-1968 | HANS-LUDWIG SCHIRNEKER | 102/438 |
| * | D | US-3,815,271 A | 06-1974 | Lynn, Robert W. | 42/84 |
| * | E | US-4,123,975 A | 11-1978 | Mohaupt, Henry H. | 102/518 |
| * | F | US-4,285,153 A | 08-1981 | Crouch, Alferd H. | 42/84 |
| * | G | US-4,433,606 A | 02-1984 | Hagelberg et al. | 89/1.812 |
| * | H | US-4,586,439 A | 05-1986 | Wrana, Josef B. V. | 102/438 |
| * | I | US-4,878,432 A | 11-1989 | Mikhail, Ameer G. | 102/309 |
| * | J | US-5,834,684 A | 11-1998 | Taylor, Robert J. | 102/517 |
| * | K | US-6,123,007 A | 09-2000 | O'Dwyer, James Michael | 89/135 |
| * | L | US-6,138,395 A | 10-2000 | O'Dwyer, James Michael | 42/84 |
| * | M | US-6,343,553 B1 | 02-2002 | O'Dwyer, James Michael | 102/438 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/512,003 | Applicant(s)/Patent Under Reexamination BAMBACH, RAMON JOHN | |
| | Examiner Benjamin P. Lee | Art Unit 3641 | Page 2 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-6,431,076 B1 | 08-2002 | O'Dwyer, James Michael | 102/525 |
| * | B | US-6,510,643 B2 | 01-2003 | O'Dwyer, James Michael | 42/84 |
| * | C | US-6,543,174 B2 | 04-2003 | O'Dwyer, James Michael | 42/76.01 |
| * | D | US-2004/0231219 A1 | 11-2004 | O'Dwyer, James Michael | 042/084 |
| * | E | US-6,862,996 B2 | 03-2005 | Key, Mark | 102/517 |
| * | F | US-2007/0028794 A1' | 02-2007 | O'Dwyer, James Michael | 102/520 |
| * | G | US-7,194,943 B2 | 03-2007 | O'Dwyer, Sean Patrick | 89/28.05 |
| * | H | US-2007/0056460 A1 | 03-2007 | O'Dwyer et al. | 102/374 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
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